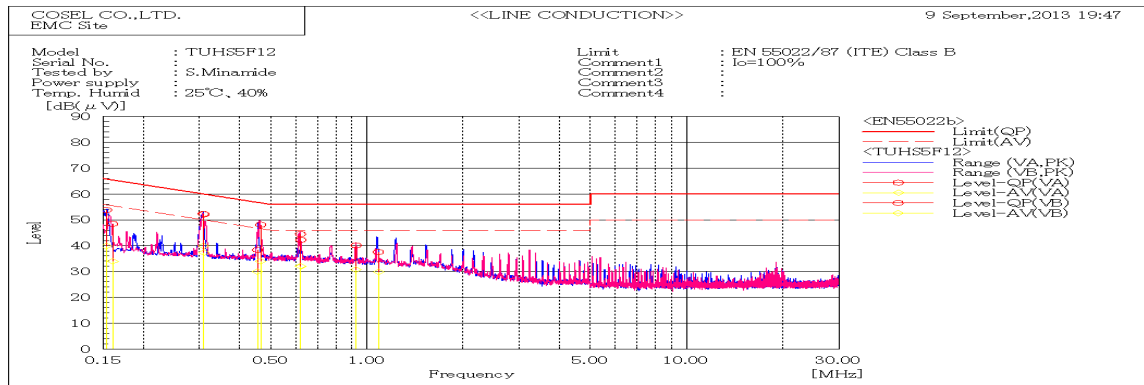
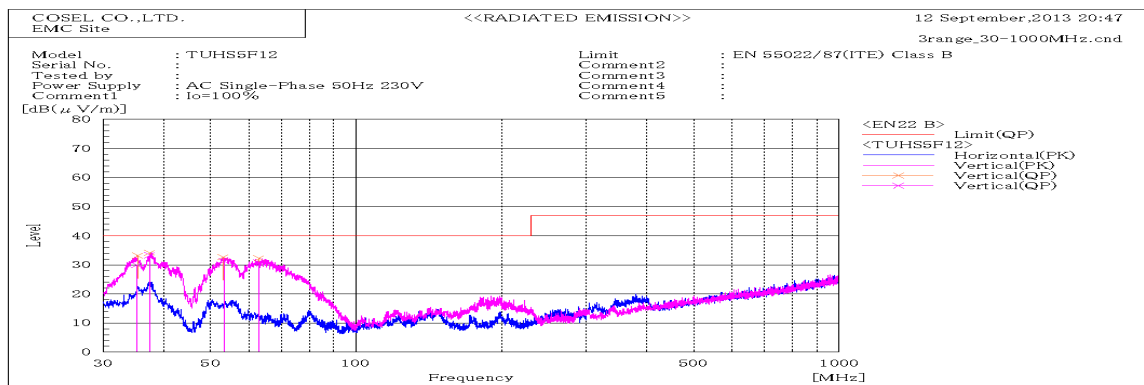


DATA SHEET

DATA SHEET		Date	16-Dec-13
Model	TUHS5F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



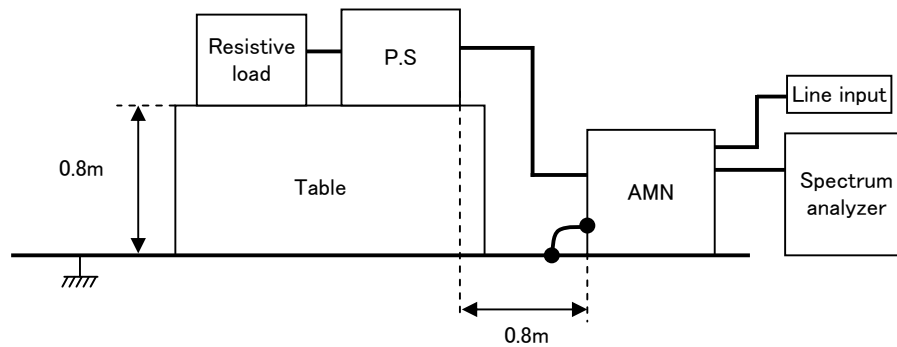
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15342		VA	33.5	19.5	20.3	53.8	39.8	65.8	55.8	12.0	16.0	Pass	
0.16043		VB	28.3	13.7	20.2	48.5	33.9	65.4	55.4	16.9	21.5	Pass	
0.30965		VB	32.1	17.3	20.1	52.2	37.4	60.0	50.0	7.8	12.6	Pass	
0.30781		VA	32.2	19.8	20.1	52.3	39.9	60.0	50.0	7.7	10.1	Pass	
0.45537		VA	18.3	9.8	20.1	38.4	29.9	56.8	46.8	18.4	16.9	Pass	
0.46576		VB	28.0	13.9	20.1	48.1	34.0	56.6	46.6	8.5	12.6	Pass	
0.62018		VB	24.4	11.9	20.1	44.5	32.0	56.0	46.0	11.5	14.0	Pass	
0.62192		VA	22.2	11.8	20.1	42.3	31.9	56.0	46.0	13.7	14.1	Pass	
0.92605		VB	19.9	10.6	20.2	40.1	30.8	56.0	46.0	15.9	15.2	Pass	
1.08721		VA	17.4	9.7	20.2	37.6	29.9	56.0	46.0	18.4	16.1	Pass	



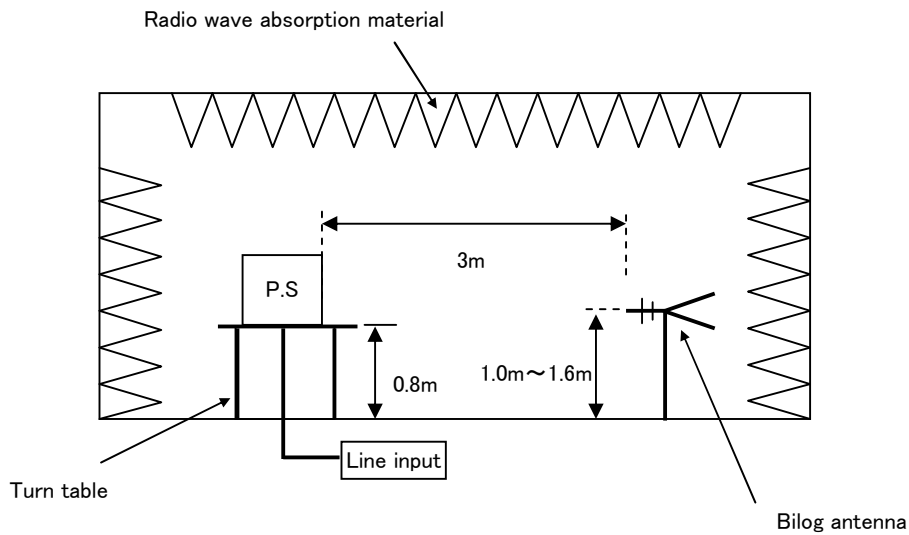
Frequency MHz	Polarization	Stability	Reading dB(uV)		Factor dB(1/m)	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
35.17	V	Stable	44.8	-14.8		30	40	40	10	Pass	100	0	
37.433	V	Stable	48.5	-15.2		33.3	40	40	6.7	Pass	102	350	
53.347	V	Stable	54.9	-23.7		31.2	40	40	8.8	Pass	102	81	
62.977	V	Stable	54.1	-23.3		30.8	40	40	9.2	Pass	113	348	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



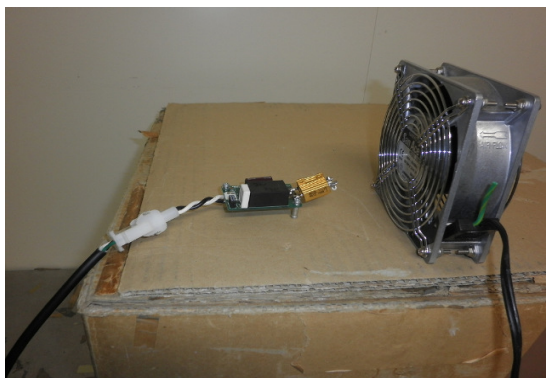
Conditions

Test: EMI

Model Name: TUHS5F□□

○ Photographs of Test Set-Up

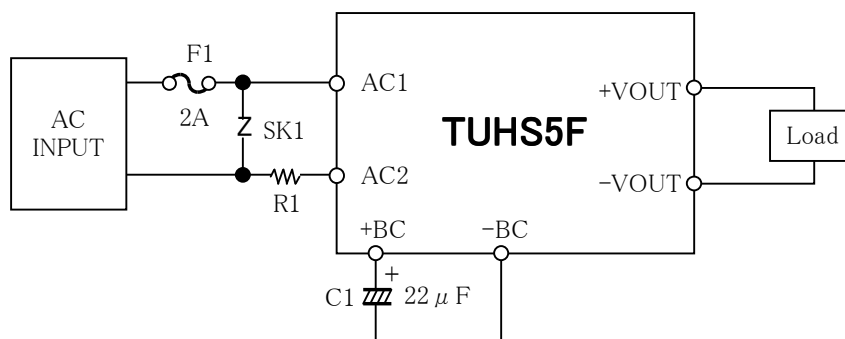
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: 1K100JA (TAMURA THERMAL DEVICE)

SK1: TND10V-511K (NIPPON CHEMI-CON)

2A

10Ω

Fig.1 Testing circuitry